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<u>L19</u>	l8 and l17		2	<u>L19</u>
<u>L18</u>	l8 and L16		0	<u>L18</u>
<u>L17</u>	(713/401-601)[CCLS]		3050	<u>L17</u>
<u>L16</u>	(714/15)[CCLS]		566	<u>L16</u>
<u>L15</u>	(714/15)![CCLS]		2	<u>L15</u>
<u>L14</u>	l9 and l4		2851	<u>L14</u>
<u>L13</u>	l10 and l4		132	<u>L13</u>
<u>L12</u>	(l10 and l4)[CCLS]		0	<u>L12</u>
<u>L11</u>	(l10 and l4)![CCLS]		0	<u>L11</u>
<u>L10</u>	(710/261-266)![CCLS]		805	<u>L10</u>
<u>L9</u>	(712/2-300)[CCLS]		10878	<u>L9</u>

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<u>L8</u>	L7 and l2	103	<u>L8</u>
<u>L7</u>	l3 near25 l4	586	<u>L7</u>
<u>L6</u>	L5 and l4	2083	<u>L6</u>
<u>L5</u>	L2 and l3	5997	<u>L5</u>
<u>L4</u>	(activat\$4 or inactivat\$4 or inhibit\$4 or disabl\$4 or enabl\$4 or hold\$4 or held) near8 (memor\$4 or stor\$4 or eprom or eeprom or rom or ram) near10 (program\$1 or instruction\$1 or cod\$3)	49792	<u>L4</u>
<u>L3</u>	select\$4 near5 address\$3	111486	<u>L3</u>
<u>L2</u>	(activat\$4 or inactivat\$4 or inhibit\$4 or disabl\$4 or enabl\$4 or hold\$4 or held or halt\$3) near6 interrupt\$3	50508	<u>L2</u>
<u>L1</u>	(activat\$4 or inactivat\$4 or inhibit\$4 or disabl\$4 or enabl\$4 or hold\$4 or held) near6 interrupt\$3	48755	<u>L1</u>

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